Interfacial Exciton Dynamics in Atomically Thin Semiconductors\textsuperscript{1}
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Dielectric confinement in atomically thin transition metal dichalcogenides (TMDs) leads to excitonic behavior that differs markedly from bulk semiconductors. Through time-resolved optical microscopy studies of exciton transport and interfacial energy transfer in monolayer MoS\textsubscript{2} and WS\textsubscript{2}, I will demonstrate the dominant role of dielectric screening in exciton-exciton interactions in this system, and how this affects our understanding of interfacial dynamics in atomically thin semiconductors.

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